Facing the Hot Chip Challenge (Again)

Bill Holt General Manager Technology and Manufacturing Group Intel Corporation

Hot Chips 17 August, 2005

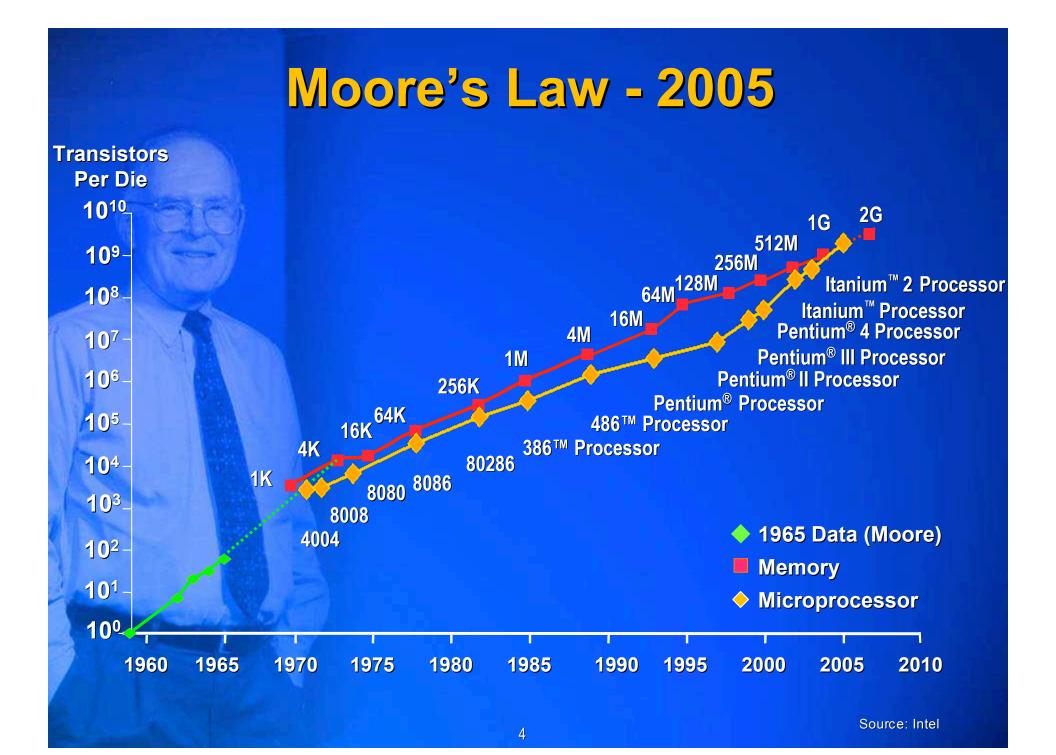
Key Messages

- The driving force behind Moore's Law
- Power has always been a consideration
- Process and design collaboration required to address power challenges
- Technology Advances provide a transistor budget to support innovation
- Efficient Design utilizes transistor budget to deliver product performance

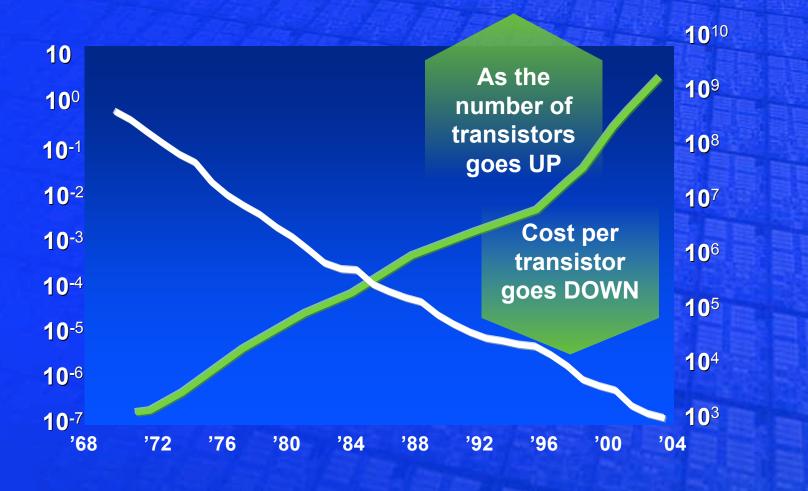
Moore's Law - 1965



Source: Intel

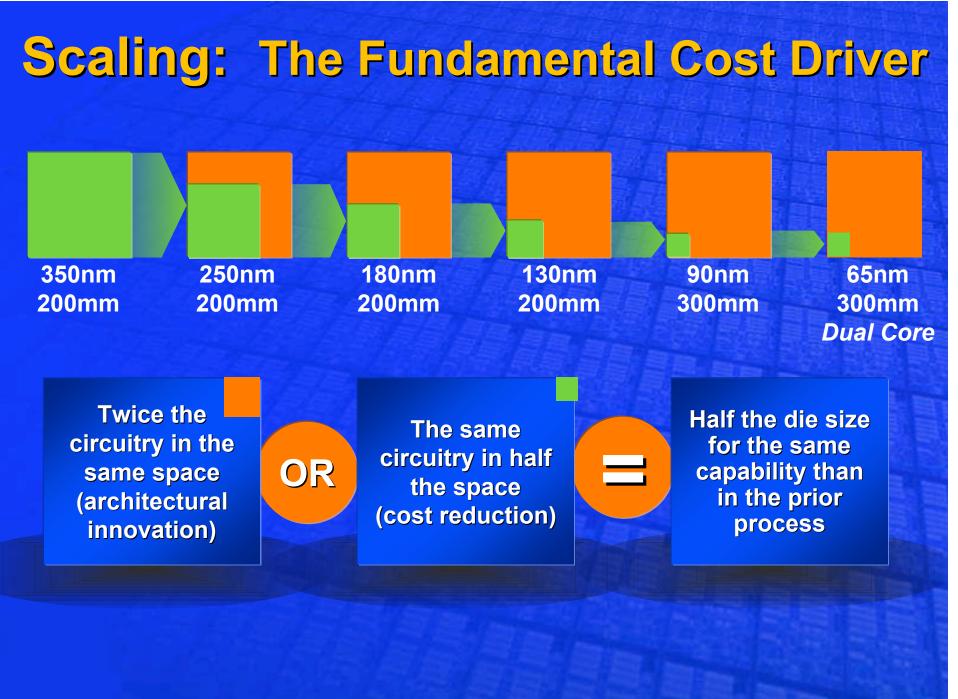


The Economics of Moore's Law

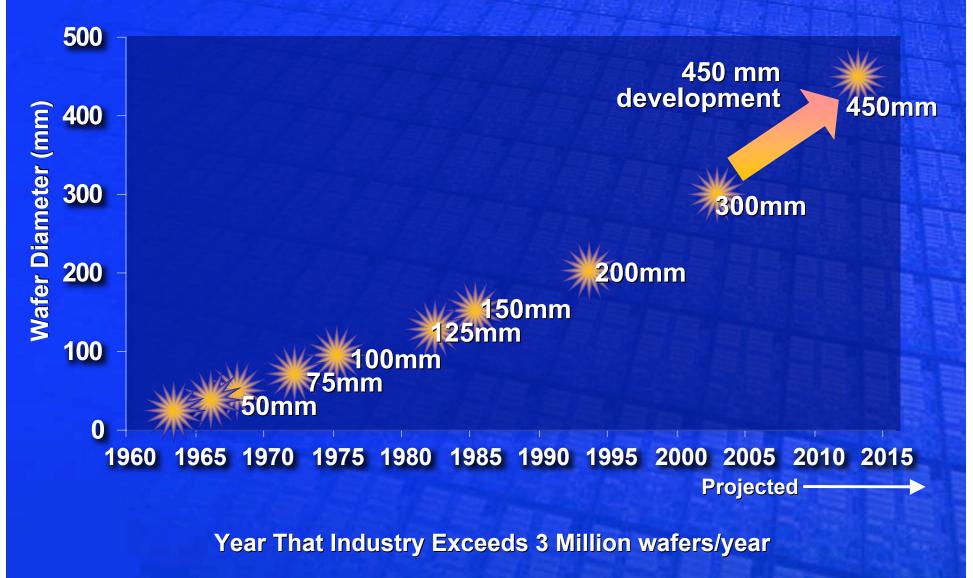


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Source: WSTS/Dataquest/Intel

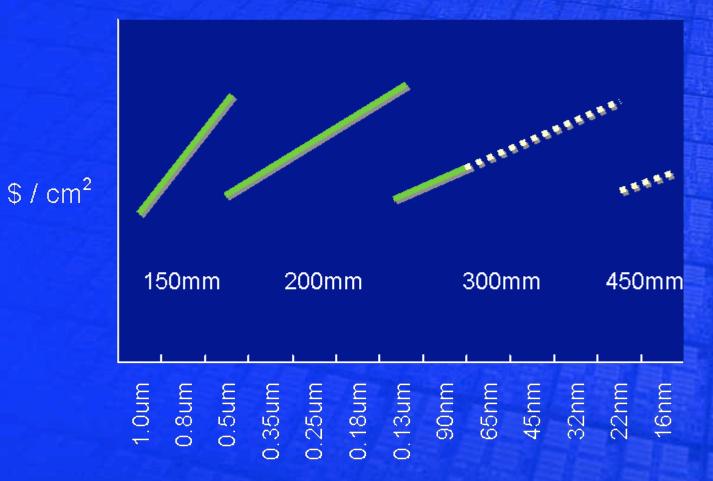


Wafer Size: Enables Cost Efficiency



Source: VLSIR

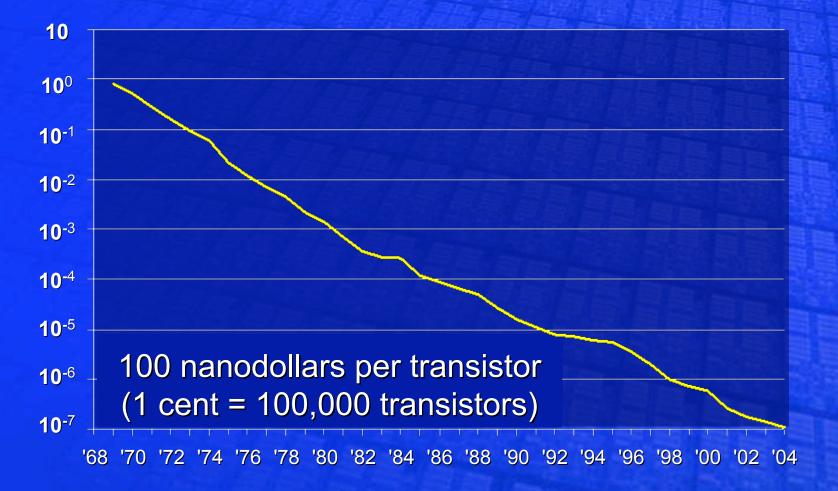
Processed Wafer Cost



Wafer size conversions offset trend of increasing wafer processing cost

Source: Intel

Moore's Law + Bigger Wafers = Lower Cost/function



Source: WSTS/Intel, 5/05

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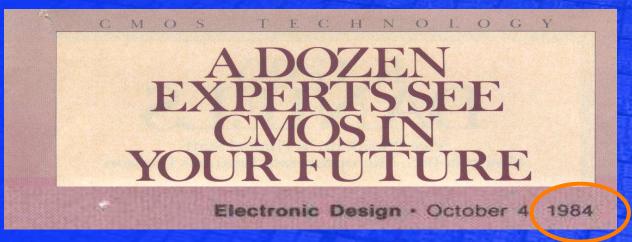
Power challenges are neither new nor fundamental

"Will it be possible to remove the heat generated by 10's of thousands of components?"

G. Moore, *Cramming more components onto integrated circuits*, Electronics, Volume 38, Number 8, April 19, **1965**



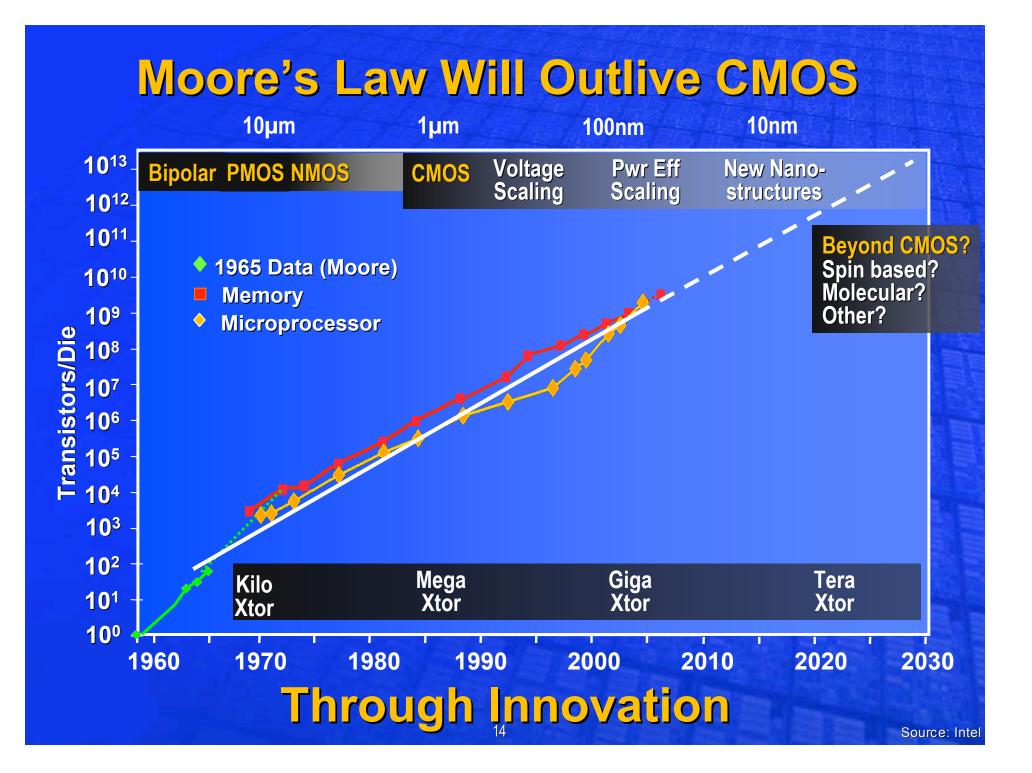
Moore's Law Preceded CMOS



"The **power barriers** now facing alternative semiconductor processes indicate that only CMOS will allow chip makers to capitalize on the density that can be achieved with gate arrays and standard cells."

"Once, maybe twice a decade the electronics industry encounters a force that affects not only the way circuits are physically designed but also the way the industry thinks. **CMOS is just such a force**." Silicon Technology has Changed to Increase Power Efficiency

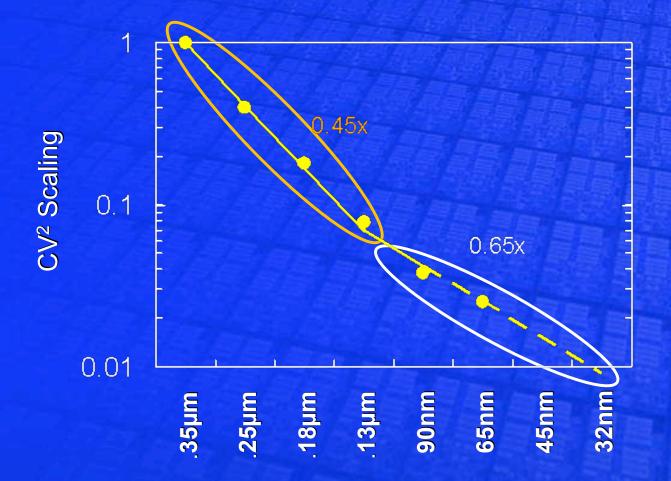
1960's: Bipolar
1970's: PMOS, NMOS
1980's: CMOS
1990's: Voltage scaling (P = CV²f)
2000's: Power efficient scaling/design



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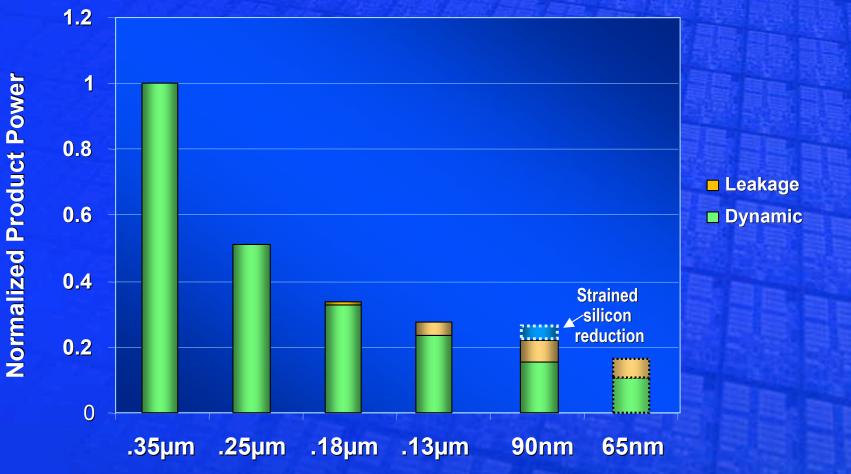
Process Advances Still Scale Power



but the rate has slowed and collaboration is required

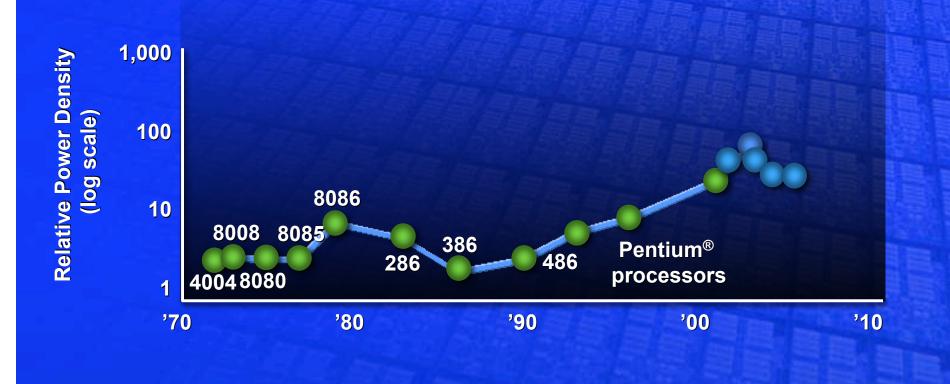
Leakage becomes Significant

Power scaling vs. process for the last 10 years (includes frequency increasing with process speed)

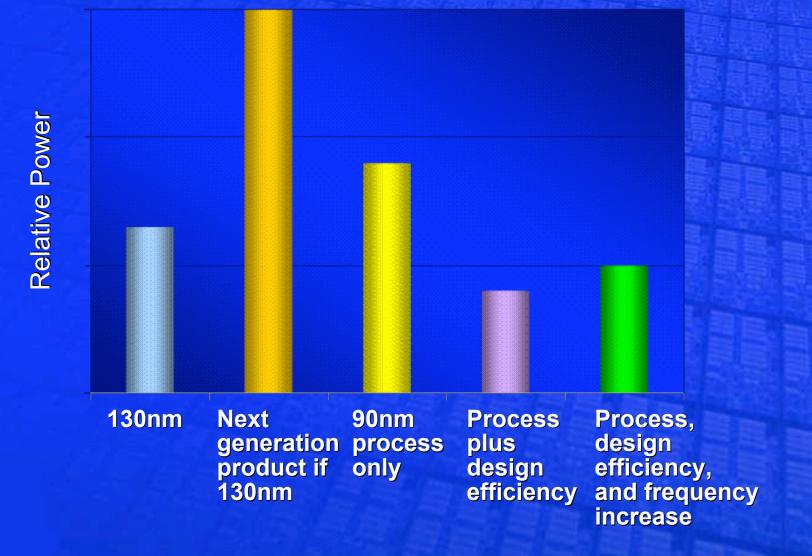


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However, Power Density Has Leveled Off



Effective Process and Design Collaboration Succeeds in Power Improvements



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Silicon Technology Advances **Feature Size Scaling** 10 10000 3.0 um 2.0 um 1.5 um 1.0 um 1000 0.8 um 0.7x every 0.5 um **3 years** 0.35 um Micron nm 0.25 um 0.18 um 0.13 um 0.1 100 90 nm 0.7x every 65 nm 45 nm 2 years 32 nm 0.01 10

New technology generation every 2 years

2000

2010

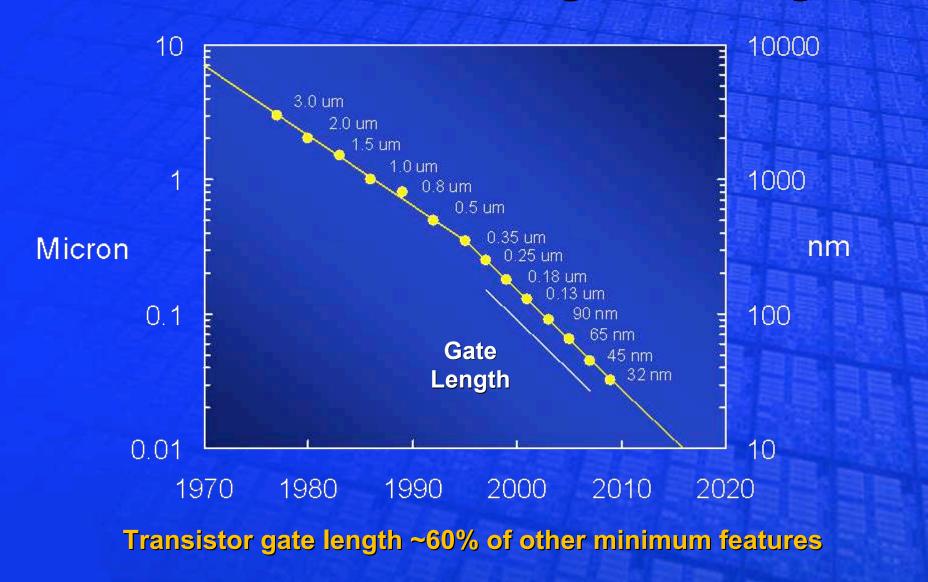
2020

1990

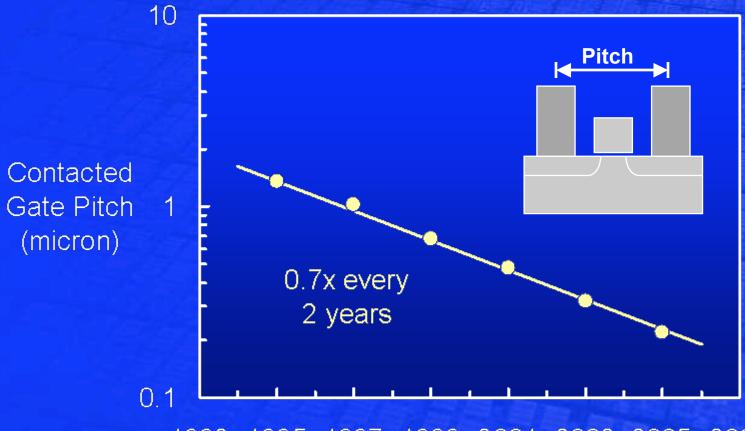
1970

1980

Transistor Gate Length Scaling



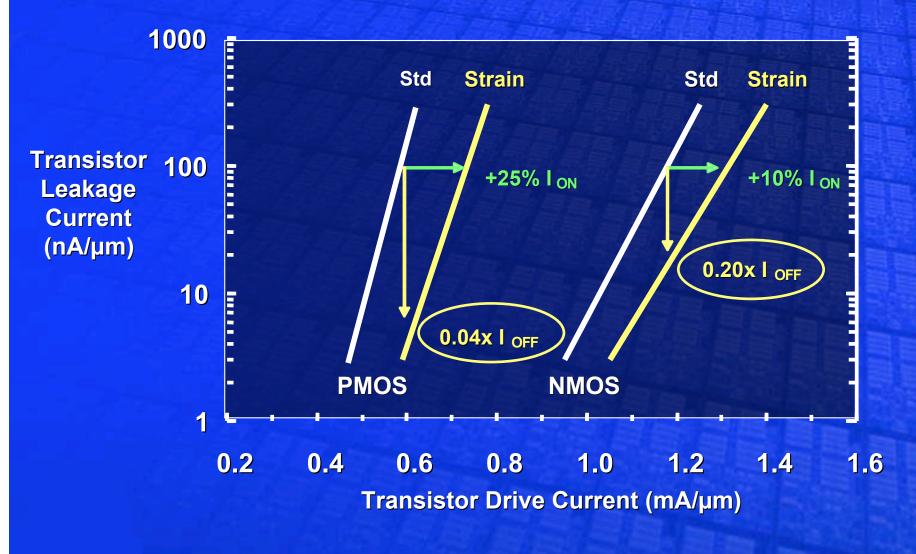
Key Density Indicator Continues to Scale



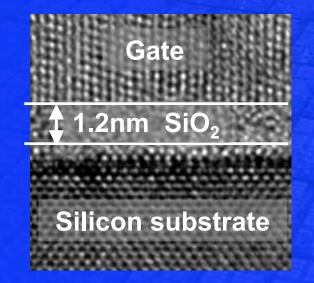
1993 1995 1997 1999 2001 2003 2005 2007

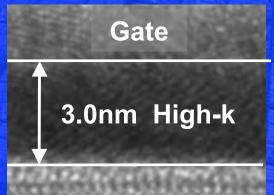
Gate pitch continues to scale 0.7x per generation, providing ~2x transistor density improvements

Strained Silicon Improves Transistor Performance and Leakage Today



High-k Dielectric Can Reduce Gate Leakage Tomorrow



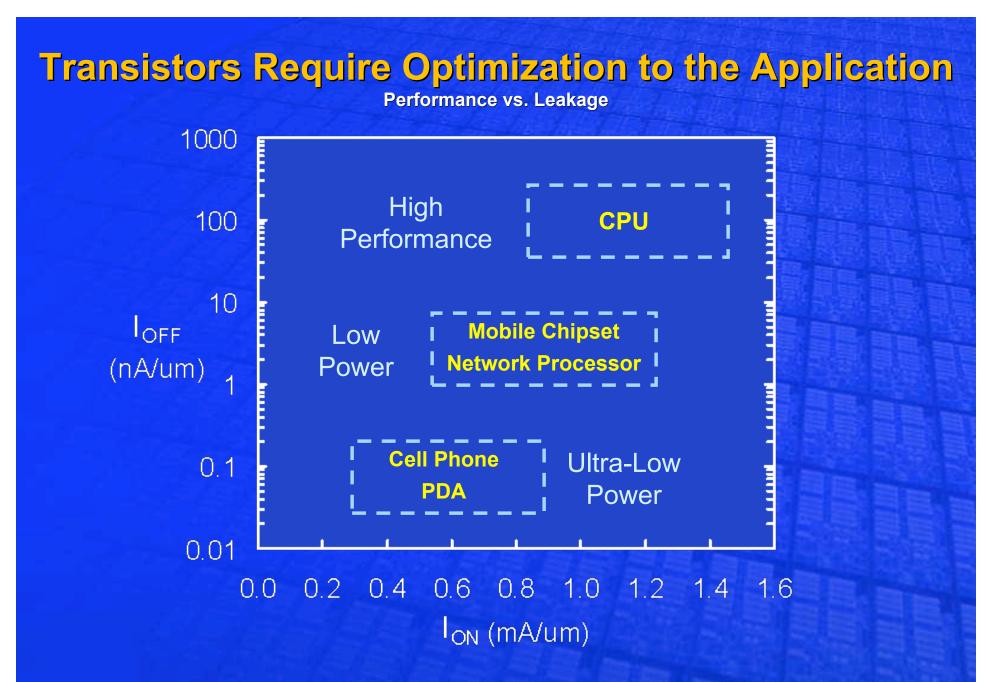


Silicon substrate

| | High-k vs. SiO ₂ | Benefit |
|----------------------------|-----------------------------|--------------------|
| Gate capacitance | 60% greater | Faster transistors |
| Gate dielectric leakage | > 100x reduction | Lower power |

Process integration is the key challenge

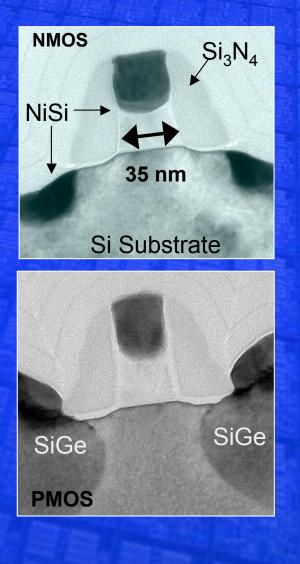
Source: Intel



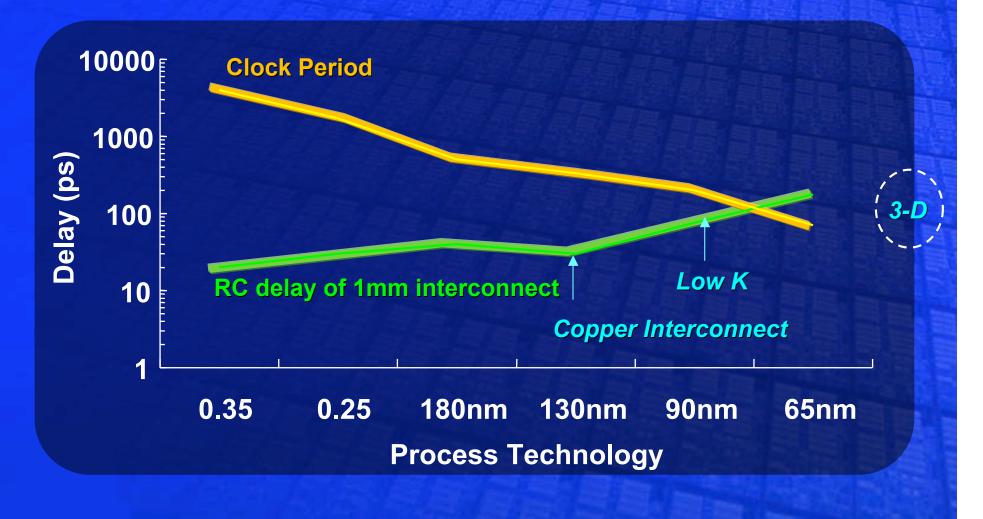
Optimized transistors can provide ~1000x lower leakage

65 nm Generation Transistors Today

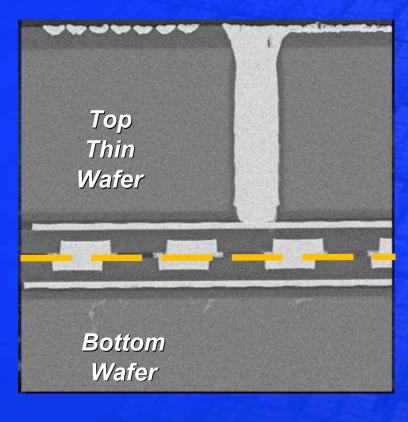
- 35 nm gate length
- 1.2 nm gate oxide
- 220 nm gate pitch
- NiSi for low resistance
- 2ND generation strained silicon for enhanced performance/power

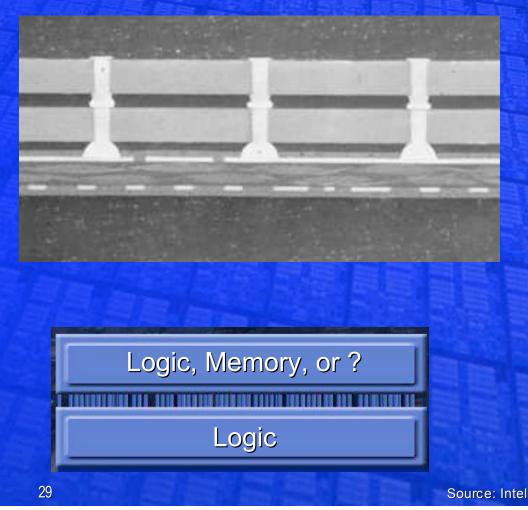


Innovations Required to Reduce Interconnect RC Challenges

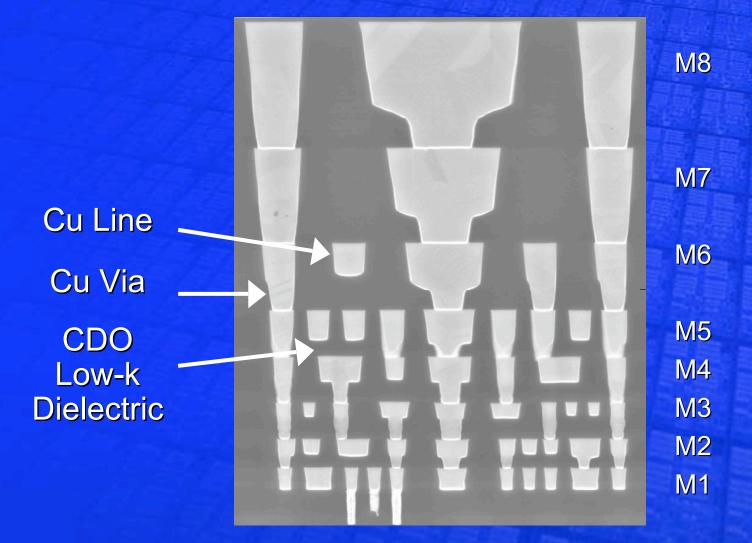


3D Silicon Stacking Wafer Die

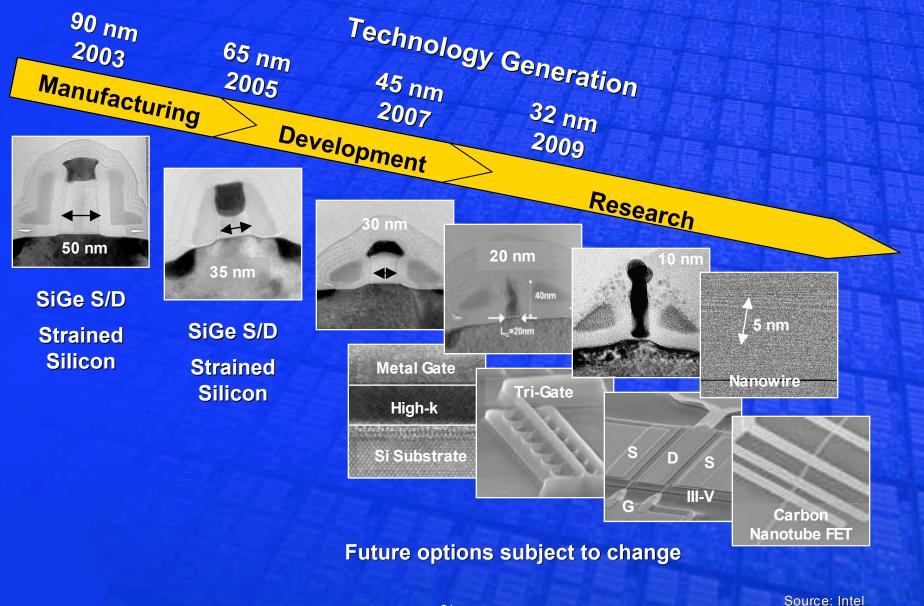




65 nm Generation Interconnects



Innovation-Enabled Pipeline in Place



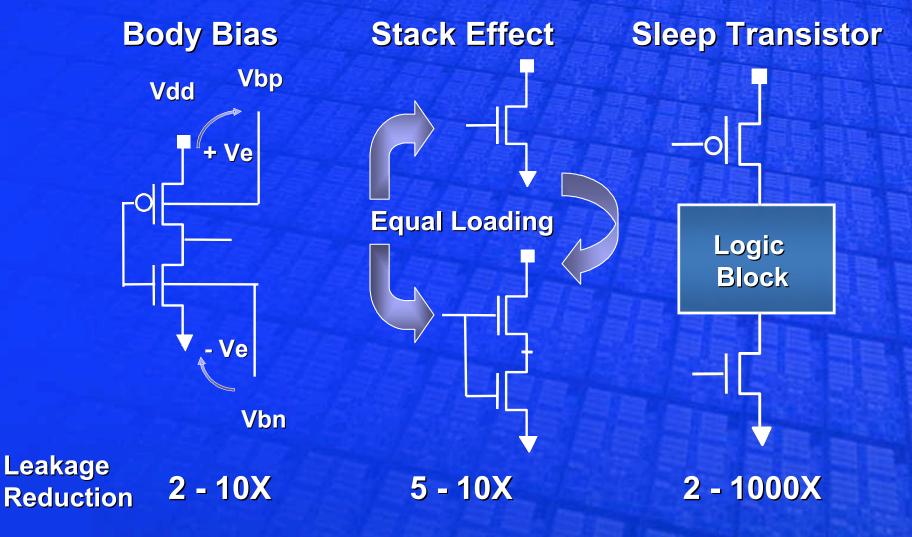
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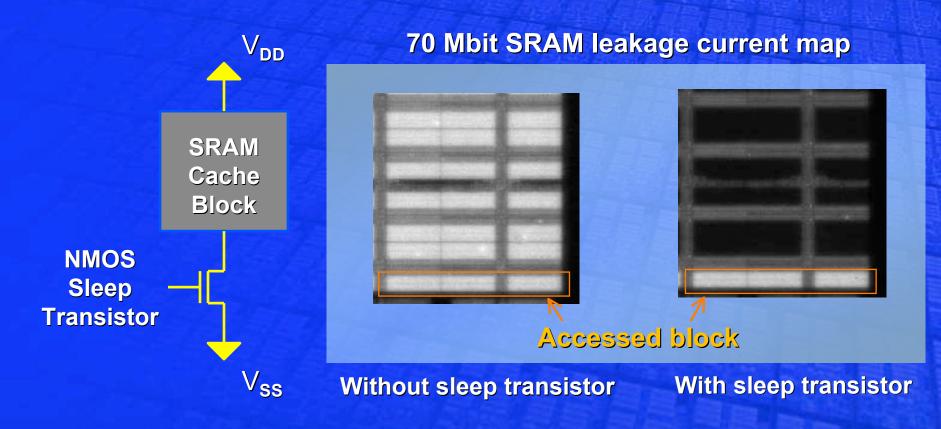
Power Reduction Techniques

- Optimum Design
- Leakage Control
- Active Power Reduction
- Increase On-die Memory
- Multi-threading
- Dual Core and Multi-core
- Special Purpose Hardware
- Function Integration through SOC/SIP

Circuit Techniques Reduce Source Drain Leakage



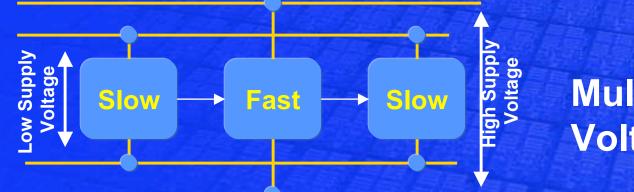
Sleep Transistor Reduces SRAM Leakage Power



>3x SRAM leakage reduction on inactive blocks

Source: Intel

Active Power Reduction

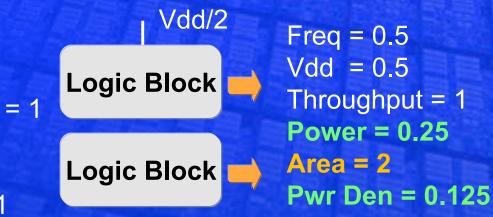


Multiple Supply Voltages

Replicated Designs



Freq = 1 Vdd = 1 Throughput = 1 Power = 1 Area = 1 Pwr Den = 1

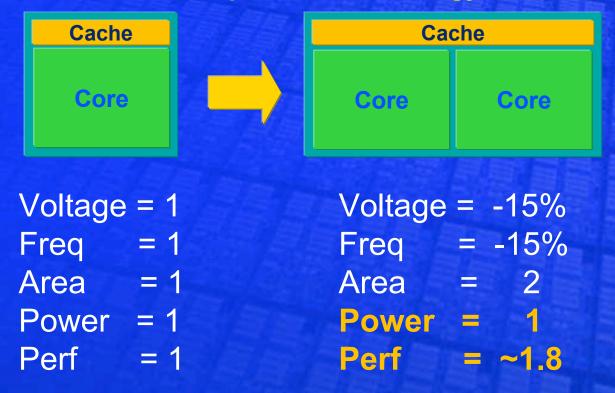


Dual Core

Rule of thumb

| Voltage | Frequency | Power | Performance |
|---------|-----------|-------|-------------|
| 1% | 1% | 3% | 0.66% |

In the same process technology...

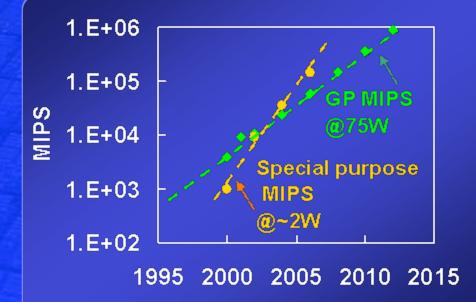


Special Purpose Hardware

Special Purpose HW Engine



2.23 mm x 3.54 mm, 260K transistors

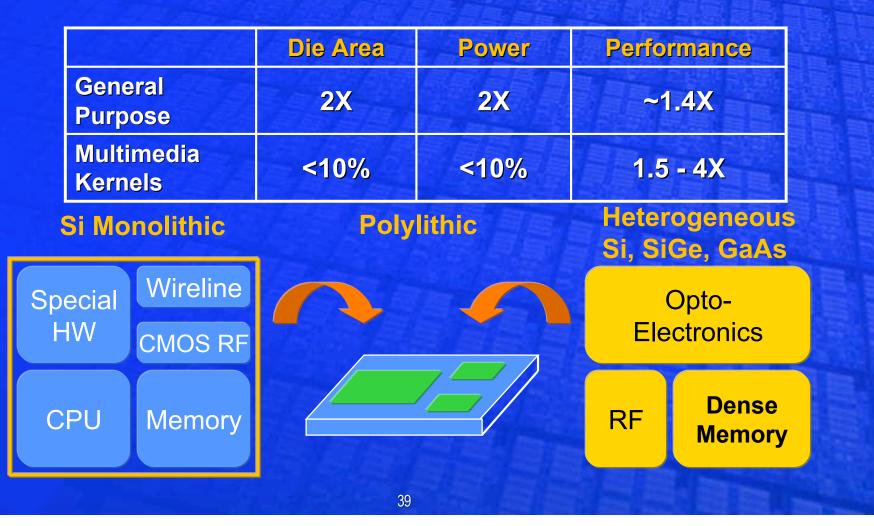


Opportunities: MPEG Encode/Decode Speech recognition Graphics

Special purpose HW—Best Mips/Watt

Value of Integration

- Special-purpose hardware -> more MIPS/mm²
- SIMD integer and FP instructions in several ISAs

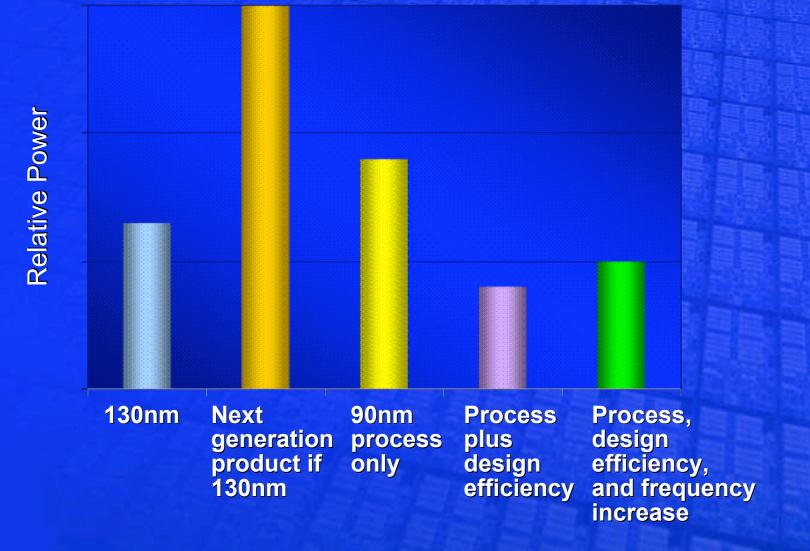


Joint Power Reduction Technology Roadmap

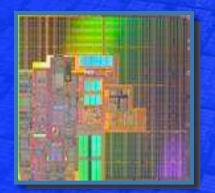
| Process Technology | Dual Vt Copper | Dual Vt (Le) Strain engineering Low K ILD | FinFET (Tri- Gate) Metal Gate 3D |
|------------------------|---|--|---|
| Circuits and Design | Sizing Clock gating | Sleep transisto Stack effect Multiple supply Body Bias | |
| Micro- Architecture | Shallower pipelines Large caches Multi-threading | Multi-threaded Multi-core Increasing multi-processing Special purpose HW | |

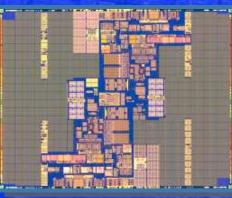
Future options subject to change

Effective Process and Design Collaboration Succeeds in Power Improvements



... and it works





| | 130 nm | 90 nm | |
|-----------------------------|----------------|------------------|--|
| | <u>Madison</u> | <u>Montecito</u> | |
| Cores/Threads | 1/1 | 2/4 | |
| Transistors | 0.41 | 1.72 Billion | |
| L3 Cache | 6 | 24 MByte | |
| Frequency | 1.5 | >1.7 GHz | |
| Relative Performance | 1 | >1.5x | |
| Thermal Design Power | 130 | ~100 Watt | |

Conclusions

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